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Application/Control No.	Applicant(s)/Patent under Reexamination			
10/540,731	TAUNIER ET AL.			
Examiner	Art Unit			
Edna Wong	1753			

	SEAR	СНЕР	
Class	Subclass	Date	Examiner
205	239	8/23/2006	EW
205	242	8/23/2006	EW
205	247	8/23/2006	EW
205	251	8/23/2006	EW
205	^{1.} 101	8/23/2006	EW
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
Inventor Search		8/23/2006	EW
EAST		8/23/2006	EW
STN		8/24/2006	EW
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